Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/801,219	MEGAW ET AL.	
Examiner	Art Unit	
Y. J. Han	2838	

SEARCHED				
Class	Subclass	Date	Examiner	
323	312			
	313	-		
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341	119			
327	539			
326	32			
323	318			
Search	updated	7/10/2006	/JH/	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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